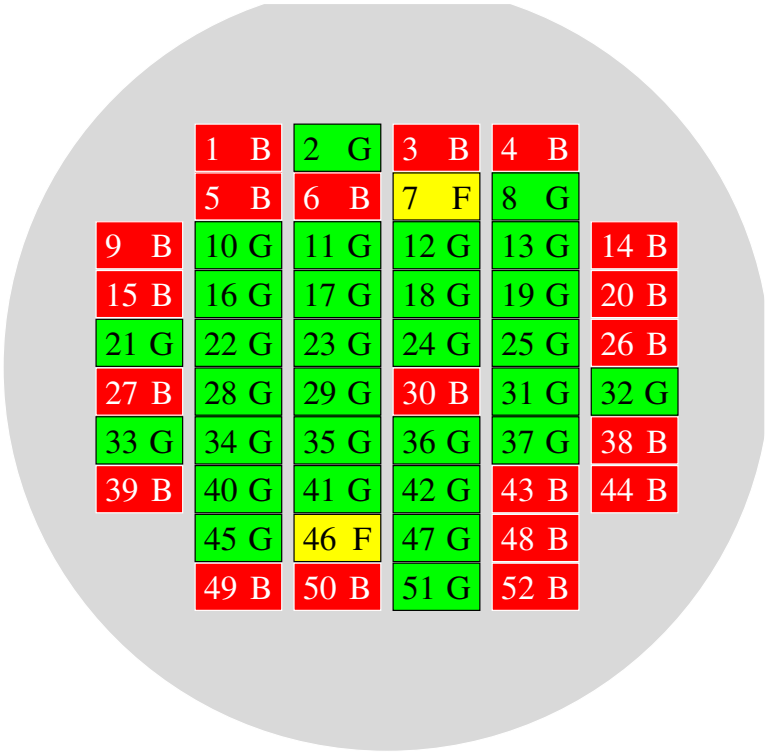
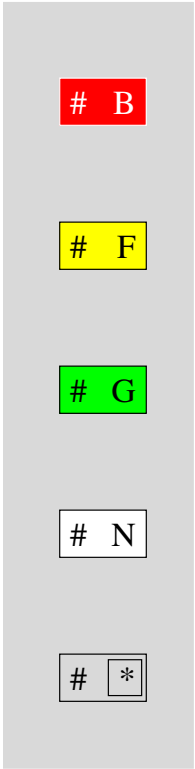
Die quality map for wafer 113 s/n: 21316-07-03

Date: 02/26/99





Bad die

Fair die

Good die

No info

Manually tagged